

In the Claims:

The pending claims are listed below. This listing of claims replaces all prior versions.

1. (previously presented) An arrangement for forming a layer over a semiconductor substrate, comprising:

means for illuminating the substrate with a plurality of illumination intensities;

means for adjusting the illumination on the substrate to determine a reflectivity of the substrate; and

means for controlling dispensing of a material over the substrate as a function of the adjusted illumination.

2. (previously presented) An arrangement for forming a layer over a semiconductor substrate, comprising:

a light source adapted to illuminate the semiconductor substrate;

a controller coupled to the light source and adapted to adjust the illumination on the substrate based on the reflectivity of the substrate, the controller further adapted to selectively control dispensing of a material over the substrate as a function of the adjusted illumination.

3. (original) The arrangement of claim 2, further including an enclosed area for forming the layer on the substrate, the enclosed area comprising walls having a non-reflective material coating thereon.

4. (original) The arrangement of claim 2, wherein the controller includes a photodiode detector.

5. (original) The arrangement of claim 2, further including an enclosed area for forming the layer on the substrate, the enclosed area comprising walls having a non-reflective material coating thereon, and wherein the controller includes a photodiode detector.

6. (original) The arrangement of claim 2, wherein the controller includes a light source controller coupled to the photodiode.

7. (previously presented) An arrangement for forming a layer over a semiconductor substrate, comprising:

- a light source adapted to illuminate the substrate with a plurality of illumination intensities;

- a dispenser that dispenses a material on the substrate;

- a first detector that detects initial contact of the material with the substrate, said detection being dependent on an optimum illumination intensity reflected from the substrate and received at the first detector; and

- a controller that adjusts the light source to produce said optimum reflected illumination received at the first detector.

8. (previously presented) An arrangement as claimed in claim 7, wherein said controller further includes a second detector that detects the illumination intensity reflected from the substrate.